

Notice of References Cited	Application/Control No. 10/774,026		Applicant(s)/Patent Under Reexamination SHENG ET AL.	
	Examiner Madeleine AV Nguyen		Art Unit 2625	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0103737 A1	08-2002	Briere, Daniel D.	705/36
*	B	US-2002/0156603 A1	10-2002	Alhadeef et al.	703/2
*	C	US-2003/0065614 A1	04-2003	Sweeney, Joan M.	705/38
*	D	US-2004/0229683 A1	11-2004	Mothwurf et al.	463/026
*	E	US-2005/0086256 A1	04-2005	Owens et al.	707/103.00R
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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